



Ifw

Attorney Docket # 34250-54

Patent

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Mykhailo SHRIBAK et al.

Serial No.: 10/616,080

Filed: July 8, 2003

For: Retardance Measurement System and Method

Examiner: Nguyen, Tu T.
Group Art: 2877

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on
August 7, 2006
(Date of Deposit)

Alfred W. Froebrich
Name of applicant, assignee, or Registered Representative

Alfred W. Froebrich
Signature

August 7, 2006
Date of Signature

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

S I R:

In compliance with the duty of disclosure under 37 C.F.R. §1.56 and in accordance with the practice under 37 C.F.R. §§1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO/SB/08a. Copies of the listed documents are also enclosed.

This information is being submitted subsequent to the later of three months after the filing date of the present application or the mailing of the first Office Action on the merits, but before the mailing of a final Action or the Notice of Allowance.

In accordance with 37 C.F.R §§1.97(g) and (h), the filing of this Information Disclosure Statement should not be construed as a representation that a search has been made or that information cited is, or is considered to be, material to patentability as defined in §1.56(b),


or that any cited document listed or attached is (or constitutes) prior art. Unless otherwise indicated, the date of publication indicated for an item is taken from the face of the item and Applicant(s) reserve(s) the right to prove that the date of publication is in fact different.

A check in the amount of \$180.00 in payment of the appropriate fee is enclosed. It is believed that no additional fees or charges are required at this time in connection with the present application. However, if any fees or charges are required at this time, they may be charged to our Patent and Trademark Office Deposit Account No. 03-2412.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO/SB/08a be returned indicating that such information has been considered.

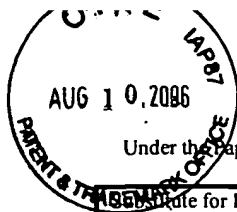
Respectfully submitted,
COHEN, PONTANI, LIEBERMAN & PAVANE LLP

By



Alfred W. Froeblich
Reg. No. 38,887
551 Fifth Avenue, Suite 1210
New York, New York 10176
(212) 687-2770

Dated: August 7, 2006



INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	Complete if Known	
	Application Number	10/616,080
	Filing Date	July 8, 2003
	First Named Inventor	Mykhailo SHRIBAK
	Art Unit	2877
	Examiner Name	Nguyen, Tu T.
Sheet 1 of 2	Attorney Docket Number	34250-54

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind-Code ² (if known)			
	AA	US-6,501,548	12-31-2002	Oldenbourg	
	AB	US-5,521,705	05-28-1996	Oldenbourg et al.	
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ : Number ⁴ Kind-Code ⁵ (if known)				
	AC	GB 2 310 925	09-10-1997	Glazer et al.		

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known	
		Application Number	10/616,080
		Filing Date	July 8, 2003
		First Named Inventor	Mykhailo SHRIBAK
		Art Unit	2877
		Examiner Name	Nguyen, Tu T.
Sheet 2 of 2	Attorney Docket Number	34250-54	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	AD	E. A. Patterson, W. Ji, and Z. Fwang, "On Image Analysis For Birefringence Measurements in Photoelasticity", <i>Optic Laser Engineering</i> , 28 , pp. 17-36, 1997	
	AE	S. Inoué, "A Method For Measuring Small Retardations of Structures in Living Cells", <i>Exp. Cell Res.</i> 2 , pp.513-517, 1951	
	AF	S.Inoué and R. Oldenbourg, <i>Microscopes</i> , in <i>Handbook of Optics</i> , M. Bass, Editor. 1995, McGraw-Hill, Inc.: New York. pp. 17.1-17.52	
	AG	M. Noguchi, T. Ishikawa, M. Ohno, and S. Tachihara, "Measurement of 2D Birefringence Distribution," in <i>International Symposium on Optical Fabrication, Testing, and Surface Evaluation</i> , Jumpei Tsujiuchi, ed., <i>Proc. SPIE</i> 1720 , 367-378, 1992	
	AH	Y. Otani, T. Shimada, T. Yoshizawa, "The Local-Sampling Phase Shifting Technique For Precise Two-Dimensional Birefringence Measurement", <i>Optical Review</i> , 1 (1), pp.103-106, 1994	
	AI	J. L. Pezzanitti, and R. A. Chipman, "Mueller Matrix Imaging Polarimetry", <i>Opt. Eng.</i> 34 (6), pp.1558-1568, 1995	
	AJ	Y. Zhu, T. Koyama, T. Takada, and Y. Murooka, "Two-Dimensional Measurement Technique For Birefringence Vector Distributions: Measurement Principle," <i>Appl. Opt.</i> 38 , pp. 2225-2231, 1999	
	AK	A. M. Glazer, J. G. Lewis, and W. Kaminsky, "An Automatic Optical Imaging System For Birefringent Media," <i>Proc. R. Soc. Lond. A</i> 452 , pp. 2751-2765, 1996	
	AL	M. I. Shribak "Autocollimating Detectors of Birefringence", in <i>International Conference on Optical Inspection and Micromasurements</i> , Christophe Gorecki, Editors, <i>Proc.SPIE</i> 2782 , pp.805-813, 1996	
	AM	M. I. Shribak, Y. Otani and T. Yoshizawa, "Return-Path Polarimeter For Two Dimensional Birefringence Distribution Measurement", <i>Polarization: Measurement, Analysis, and Remote Sensing II</i> , Dennis H., Goldstein; and David B. Chenault; Eds. <i>Proc., SPIE</i> 3754 , pp. 144-149, 1999	

Examiner Signature		Date Considered	
--------------------	--	-----------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * Applicant's unique citation designation number (optional). * See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. * Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). * For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. * Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. * Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.